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Team Nexperia

Product data sheet

Product profile

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology.

1.2 Features

- Logic level threshold
- Optimized for use in DC-to-DC converters
- 100 % R_G tested

- Lead-free package
- Very low switching and conduction losses
- 100 % ruggedness tested

1.3 Applications

- DC-to-DC converters
- Voltage regulators

- Switched-mode power supplies
- PC Motherboards

1.4 Quick reference data

- $V_{DS} \le 30 \text{ V}$
- Arr R_{DSon} $\leq 4.8 \text{ m}\Omega$

- $I_D \le 84 A$
- $Q_{GD} = 5.4 \text{ nC (typ)}$

Pinning information

Pinning Table 1.

Pin	Description	Simplified outline	Symbol
1, 2, 3	source (S)		
4	gate (G)	mb	D
mb	mounting base; connected to drain (D)	1 2 3 4	mbb076 S
		SOT669 (LFPAK)	



N-channel TrenchMOS logic level FET

3. Ordering information

Table 2. Ordering information

Type number	Package		
	Name	Description	Version
PH4830L	LFPAK	plastic single-ended surface-mounted package (Ifpak); 4 leads	SOT669

4. Limiting values

Table 3. Limiting values

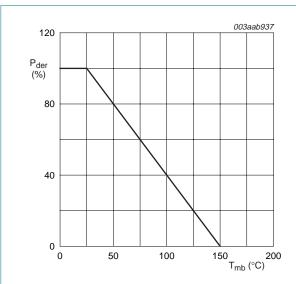
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	25 °C ≤ T _j ≤ 150 °C	-	30	V
V_{DGR}	drain-gate voltage (DC)	$25~^{\circ}\text{C} \le \text{T}_{j} \le 150~^{\circ}\text{C}; \text{R}_{\text{GS}} = 20~\text{k}\Omega$	-	30	V
V_{GS}	gate-source voltage		-	±20	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 2</u> and <u>3</u>	-	84	Α
		T_{mb} = 100 °C; V_{GS} = 10 V; see Figure 2	-	63	Α
I_{DM}	peak drain current	T_{mb} = 25 °C; pulsed; $t_p \le 10 \mu s$; see Figure 3	-	240	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 1</u>	-	62.5	W
T _{stg}	storage temperature		-55	+150	°C
Tj	junction temperature		-55	+150	°C
Source-o	Irain diode				
Is	source current	T _{mb} = 25 °C	-	52	Α
I _{SM}	peak source current	T_{mb} = 25 °C; pulsed; $t_p \le 10 \mu s$	-	208	Α
Avalance	ne ruggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	unclamped inductive load; I_D = 49 A; t_p = 0.12 ms; $V_{DS} \le$ 25 V; R_{GS} = 50 Ω ; V_{GS} = 10 V; starting at T_j = 25 °C	-	121	mJ

Product data sheet

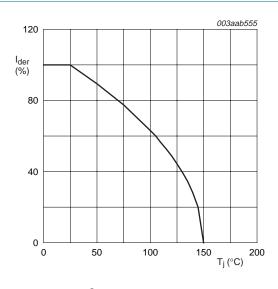
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$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100 \%$$

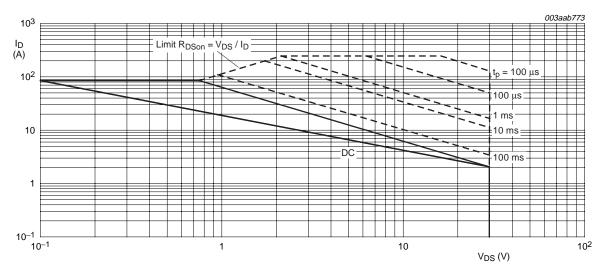
Fig 1. Normalized total power dissipation as a function of mounting base temperature



$$I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100 \%$$

Fig 2. Normalized continuous drain current as a function of mounting base temperature

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 T_{mb} = 25 °C; I_{DM} is single pulse

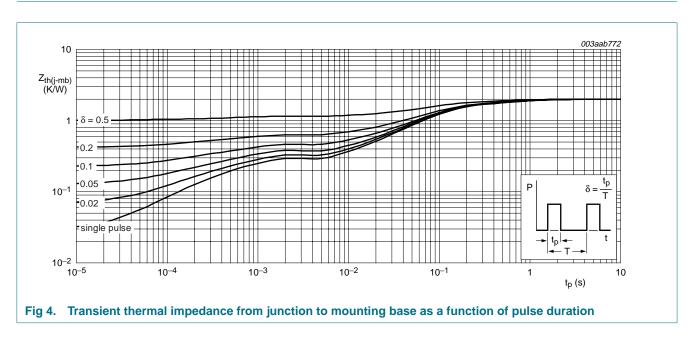
Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

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5. Thermal characteristics

Table 4. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	2	K/W



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6. Characteristics

 Table 5.
 Characteristics

 $T_j = 25 \,^{\circ}C$ unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static ch	naracteristics					
$V_{(BR)DSS}$	drain-source breakdown	$I_D = 250 \mu\text{A}; V_{GS} = 0 V$				
	voltage	T _j = 25 °C	30	-	-	V
		$T_j = -55$ °C	27	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$; see <u>Figure 9</u> and <u>10</u>				
		T _j = 25 °C	1.3	1.7	2.15	V
		T _j = 150 °C	8.0	-	-	V
		$T_j = -55 ^{\circ}\text{C}$	-	-	2.6	V
I _{DSS}	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}$				
		T _j = 25 °C	-	-	1.0	μΑ
		T _j = 150 °C	-	-	100	μΑ
I _{GSS}	gate leakage current	$V_{GS} = \pm 20 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	100	nA
R_G	gate resistance	f = 1 MHz	-	0.51	-	Ω
R _{DSon}	drain-source on-state	$V_{GS} = 10 \text{ V}$; $I_D = 25 \text{ A}$; see Figure 6 and 8	27 1.3 0.8			
	resistance	T _j = 25 °C	-	3.8	4.8	$m\Omega$
		T _j = 150 °C	-	6.3	7.7	$m\Omega$
		$V_{GS} = 4.5 \text{ V}$; $I_D = 25 \text{ A}$; see Figure 6 and 8	-	5.6	7.0	$m\Omega$
Dynamic	characteristics					
$Q_{G(tot)}$	total gate charge	$I_D = 25 \text{ A}$; $V_{DS} = 12 \text{ V}$; $V_{GS} = 4.5 \text{ V}$;	-	22.9	-	nC
Q_{GS}	gate-source charge	see Figure 11 and 12	-	9.0	-	nC
Q _{GS1}	pre-V _{GS(th)} gate-source charge		-	5.5	-	nC
Q _{GS2}	post-V _{GS(th)} gate-source charge		-	3.5	-	nC
Q_{GD}	gate-drain charge		-	5.4	-	nC
$V_{GS(pl)}$	gate-source plateau voltage		-	2.8	-	V
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 12 \text{ V}; f = 1 \text{ MHz};$	-	2786	-	рF
C _{oss}	output capacitance	see <u>Figure 14</u>	-	579	-	рF
C _{rss}	reverse transfer capacitance		-	297	-	pF
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 0 \text{ V}; f = 1 \text{ MHz}$	-	3300	-	pF
t _{d(on)}	turn-on delay time	V_{DS} = 12 V; R_L = 0.5 Ω ; V_{GS} = 4.5 V;	-	28	-	ns
t _r	rise time	$R_G = 5.6 \Omega$	-	43	-	ns
t _{d(off)}	turn-off delay time			35	-	ns
t _f	fall time		-	19	-	ns
Source-	drain diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}$; $V_{GS} = 0 \text{ V}$; see Figure 13	-	0.85	-	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s}; V_{GS} = 0 \text{ V};$	-	47	-	ns
Q _r	recovered charge	$V_{R} = 30 \text{ V}$	-	17	-	nC

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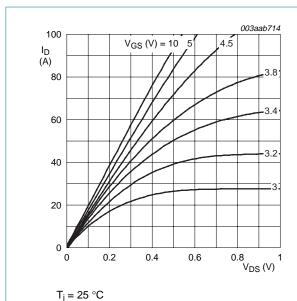


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values

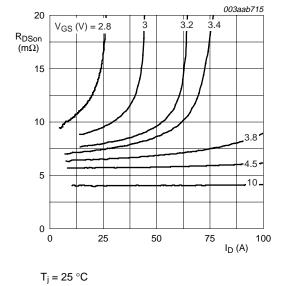
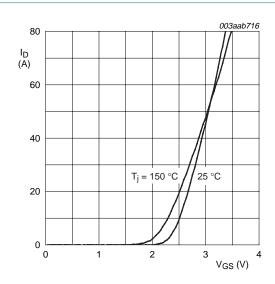
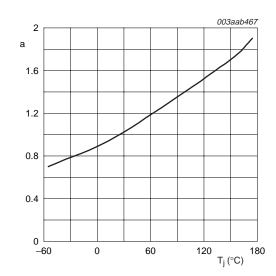


Fig 6. Drain-source on-state resistance as a function of drain current; typical values



 T_j = 25 °C and 150 °C; $V_{DS} > I_D \times R_{DSon}$



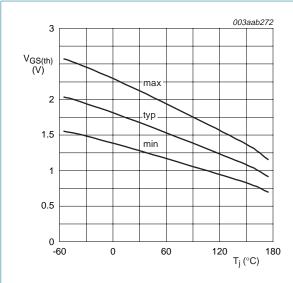


$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

Fig 8. Normalized drain-source on-state resistance factor as a function of junction temperature

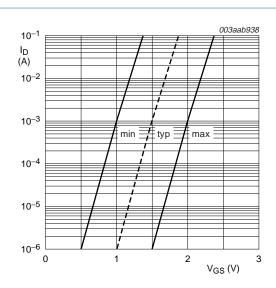
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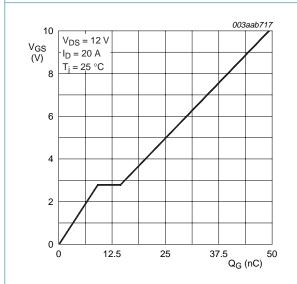
 $I_D = 1 \text{ mA}; V_{DS} = V_{GS}$

Fig 9. Gate-source threshold voltage as a function of junction temperature



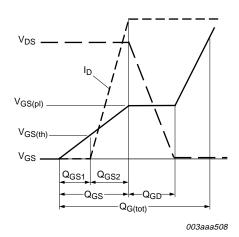
 $T_i = 25 \,^{\circ}C; \, V_{DS} = 5 \,^{\circ}V$

Fig 10. Sub-threshold drain current as a function of gate-source voltage



 $I_D = 20 \text{ A}; V_{DS} = 12 \text{ V}$

Fig 11. Gate-source voltage as a function of gate charge; typical values



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Fig 12. Gate charge waveform definitions

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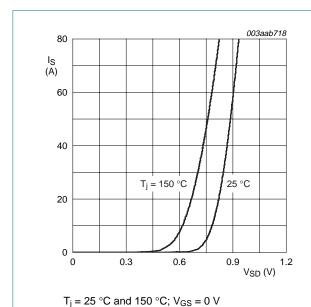
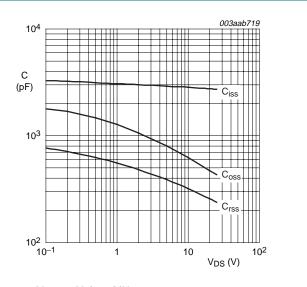


Fig 13. Source current as a function of source-drain voltage; typical values



 $V_{GS} = 0 V$; f = 1 MHz

Fig 14. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

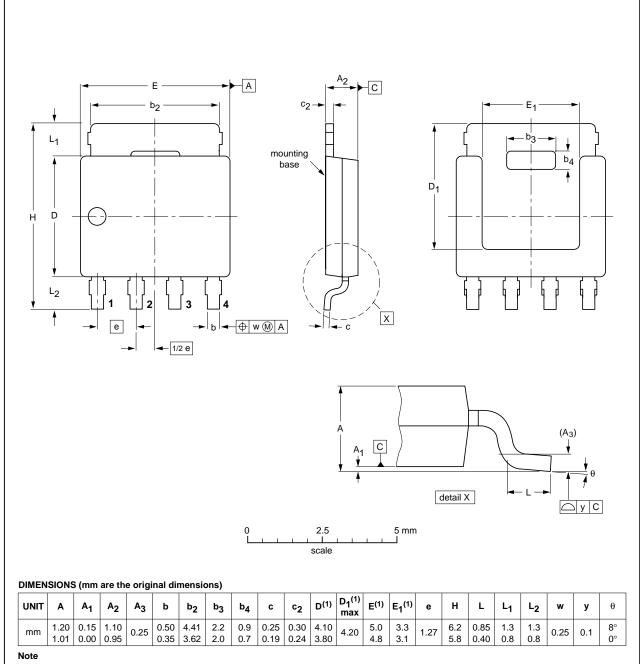
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Package outline

Plastic single-ended surface-mounted package (LFPAK); 4 leads

SOT669

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1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	ENCES		EUROPEAN ISS	ISSUE DATE
VERSION	IEC	JEDEC	JEITA			ISSUE DATE
SOT669		MO-235				04-10-13 06-03-16

Fig 15. Package outline SOT669 (LFPAK)

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N-channel TrenchMOS logic level FET

Revision history

Table 6. **Revision history**

Document ID	Release date	Data sheet status	Change notice	Supersedes
PH4830L_1	20070906	Product data sheet	-	-

N-channel TrenchMOS logic level FET

Legal information

9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- Please consult the most recently issued document before initiating or completing a design.
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